

Report Semiconductor Technology

Should include:

- I/V measurement “wafer with epi-layer”
 - evaluation of ideality factor n
 - Breakdown voltage
- C/V measurement “wafer with epi-layer”
 - Estimated doping profile in the epi layer
 - Estimated thickness of epi layer
- Radiation measurement on manufactured detector
 - Uranium spectra with conversion from channel to energy “least square method by using straight line”
 - Estimation of the peak energy of the unknown ^{241}Am spectra

The description of the processing of detector is reported in the sensor component course